

Search Notes

Application/Control No.

10/697,647

Examiner

Thuy V. Tran

Applicant(s)/Patent under
Reexamination

HAMASHIMA ET AL.

Art Unit

2821

SEARCHED

Class	Subclass	Date	Examiner
—	Updated Search	2/28/2006	T.T.

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR